

Notice of References Cited	Application/Control No. 10/608,204		Applicant(s)/Patent Under Reexamination BAYARDO ET AL.	
	Examiner MARK P. FRANCIS		Art Unit 2193	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,081,812 A	06-2000	Boggs et al.	707/202
*	B	US-2003/0088571 A1	05-2003	Ekkel, Erik	707/100
*	C	US-2004/0044648 A1	03-2004	Anfindsen et al.	707/001
*	D	US-2004/0064512 A1	04-2004	Arora et al.	709/206
*	E	US-2004/0098447 A1	05-2004	Verbeke et al.	709/201
*	F	US-2004/0148326 A1	07-2004	Nadgir et al.	709/200
*	G	US-2004/0143666 A1	07-2004	Xu et al.	709/227
*	H	US-2004/0215625 A1	10-2004	Svensen et al.	707/010
*	I	US-2005/0138110 A1	06-2005	Redlich et al.	709/201
*	J	US-4,931,928	06-1990	Greenfeld, Norton R.	717/131
*	K	US-5,862,382	01-1999	Kataoka, Yoshio	717/131
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.